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TSMC-03-375

April 30, 2004

To: Commissioner for Patents

P.O.Box 1450

Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572

28 Davis Avenue

Poughkeepsie, N.Y. 12603

Subject:

Serial No. 10/798,178 03/11/04

Cheng-Ku Chen et al.

METHOD OF FORMING POLYSILICON GATE STRUCTURES WITH SPECIFIC EDGE PROFILES FOR OPTIMIZATION OF LDD OFFSET SPACING

OFFBET SPACING

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation In An Application.

The following Patents and/or Publications are submitted to comply with the duty of disclosure under CFR 1.97-1.99 and 37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on May $\frac{4}{3}$, 2004.

Stephen B. Ackerman, Reg.# 37761

Signature/Date _____

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- U.S. Patent 6,514,830 to Fang et al., "Method of Manufacturing High Voltage Transistor with Modified Field Implant Mask," discloses a method of manufacturing a high voltage transistor exhibiting high gated diode breakdown voltage, low leakage and low body effect while avoiding an excessive number of costly masking steps.
- U.S. Patent 6,350,639 to Yu et al., "Simplified Graded LDD Transistor Using Controlled Polysilicon Gate Profile," discusses a manufacturing method for Metal-Oxide-Semiconductors (MOS) which employ lightly doped drain (LDD) structures.
- U.S. Patent 6,025,240 to Chan et al., "Method and System for Using a Spacer to Offset Implant Damage and Reduce Lateral Diffusion in Flash Memory Devices," discloses a system and method for providing a memory cell on a semiconductor.
- U.S. Patent 6,294,432 to Lin et al., "Super Halo Implant Combined with Offset Spacer Process," discloses a method for forming a semiconductor structure by using super halo implant combined with offset spacer process.

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U.S. Patent 6,187,644 to Lin et al., "Method of Removing Oxynitride by Forming an Offset Spacer," discloses a method for forming a semiconductor device.

Sincerely

Stephen B. Ackerman, Reg. No. 37761

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